

**LMPP3925EX6F 30V P-Channel Enhancement Mode MOSFET**
**Features**

- -30V/-0.3A,  $R_{DS(ON)}=2500m\Omega@V_{GS}=-4.5V$   
 $R_{DS(ON)}=2900m\Omega@V_{GS}=-2.5V$   
 $R_{DS(ON)}=5000m\Omega@V_{GS}=-1.8V$
- Low-Voltage Operation
- High-Speed Circuits
- ESD Protection
- SOT-363 package design

**Product Description**

LMPP3925EX6F, P-Channel enhancement mode MOSFET, uses Advanced Trench Technology to provide excellent  $R_{DS(ON)}$ , low gate charge.

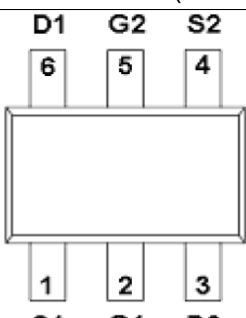
These devices are particularly suited for low

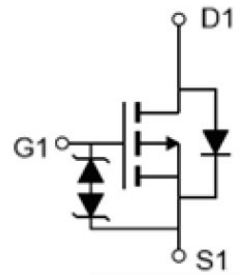
voltage power management, such as smart phone and notebook computer, and low in-line power loss are needed in commercial industrial surface mount applications.

**Applications**

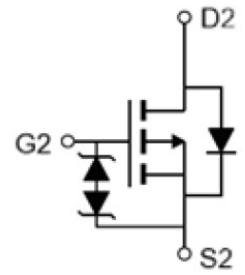
- Drivers: Relays, Solenoids, Lamps, Hammers
- Battery Operated Systems
- Power Supply Converter Circuits
- Load/Power Switching Smart Phones, Pagers

**Pin Configuration**

LMPP3925EX6F (SOT-363)		
		
PIN	Description	
1	Source1	
2	Gate1	
3	Drain2	
4	Source2	
5	Gate2	
6	Drain1	



p-channel



p-channel

**Ordering Information**

Ordering Information					
Part Number	P/N	PKG code	Pb Free code	Package	Quantity
LMPP3925EX6F	LMPP3925E	X6	F	SOT-363	3000pcs

**Marking Information**

Marking Information	
Part Number	LFC code
<u>5</u>	WM

**Absolute Maximum Ratings**

(T<sub>C</sub>=25°C Unless otherwise noted)

Symbol	Parameter	Typical	Unit
V <sub>DSS</sub>	Drain-Source Voltage	-30	V
V <sub>GSS</sub>	Gate-Source Voltage	±10	V
I <sub>D</sub>	Continuous Drain Current (T <sub>J</sub> =150°C)	T <sub>A</sub> =25°C	A
		T <sub>A</sub> =70°C	
I <sub>DM</sub>	Pulsed Drain Current	-1.2	A
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> =25°C	W
		T <sub>A</sub> =70°C	
T <sub>J</sub>	Operating Junction Temperature	-55 to +150	°C
T <sub>STG</sub>	Storage Temperature Range	-55 to +150	°C
R <sub>θJA</sub>	Thermal Resistance Junction to ambient	400	°C/W

Note1. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

**Electrical Characteristics**

(T<sub>C</sub>=25°C Unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA	-30			V
V <sub>GS (th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250uA	-0.4		-1.0	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±8V			±10	nA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V			-1	uA
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-0.5A, V <sub>GS</sub> =0V			-1.3	V
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-0.5A		1.5	2.5	mΩ
		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-0.2A		1.9	2.9	
		V <sub>GS</sub> =-1.8V, I <sub>D</sub> =-0.1A		2.4	50	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-10V, I <sub>D</sub> =-0.25A		550		mS
Dynamic						
Q <sub>g</sub>	Total Gate Charge	V <sub>DD</sub> =-15V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-1A		1.0		nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DD</sub> =-15V, V <sub>GS</sub> =-8V, I <sub>D</sub> =-1A		0.2		
Q <sub>gd</sub>	Gate-Drain Charge	I <sub>D</sub> =-1A		0.1		
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, f=1.0MHz		54		pF
C <sub>oss</sub>	Output Capacitance			10.9		
C <sub>rss</sub>	Reverse Transfer Capacitance			5.8		
t <sub>d(on)</sub>	Turn-On Time	V <sub>DD</sub> =-10V, R <sub>L</sub> =47Ω, V <sub>GEN</sub> =-4.5V, I <sub>D</sub> =-0.2A, R <sub>G</sub> =10Ω		3.8		ns
t <sub>r</sub>				11		
t <sub>d(off)</sub>	Turn-Off Time			45		
t <sub>f</sub>				20		

## Typical Performance Characteristics

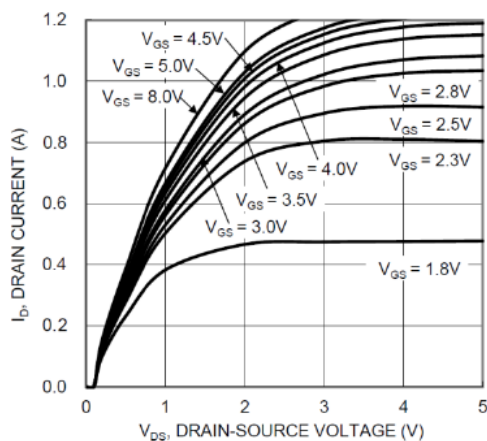


Fig. 1 Typical Output Characteristics

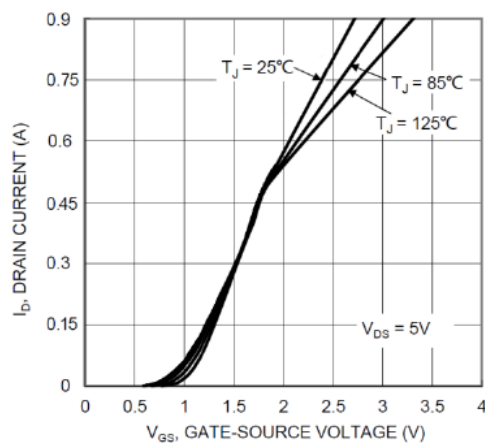


Fig. 2 Typical Transfer Characteristics

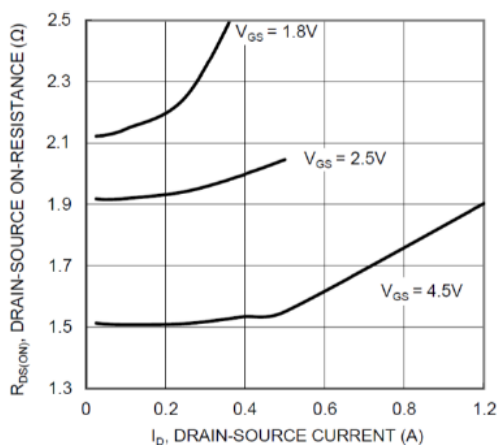


Fig. 3 Typical On-Resistance vs.  $I_D$  and  $V_{GS}$

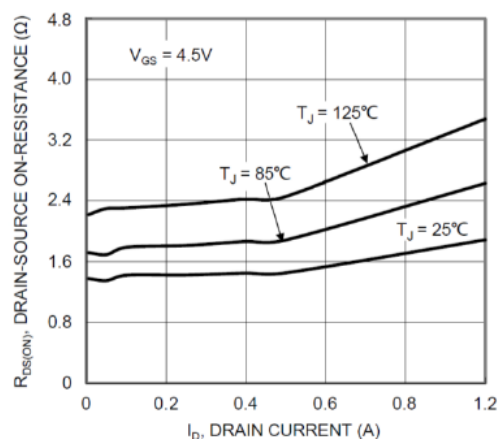


Fig. 4 Typical Drain-Source On-Resistance vs.  $I_D$  and  $T_J$

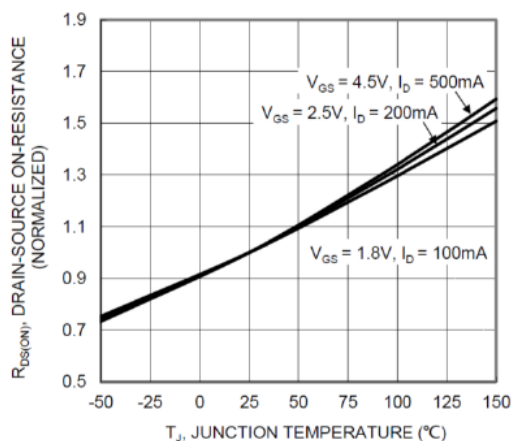


Fig. 5 On-Resistance Variation with  $T_J$

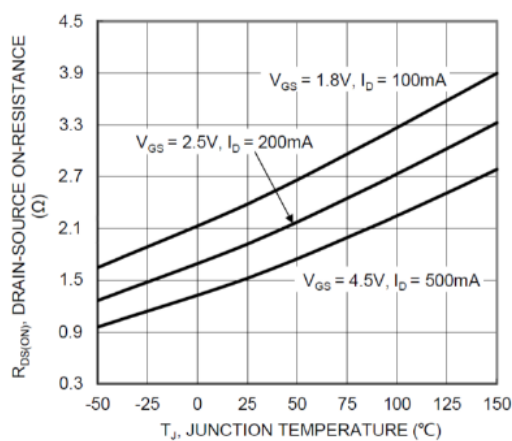
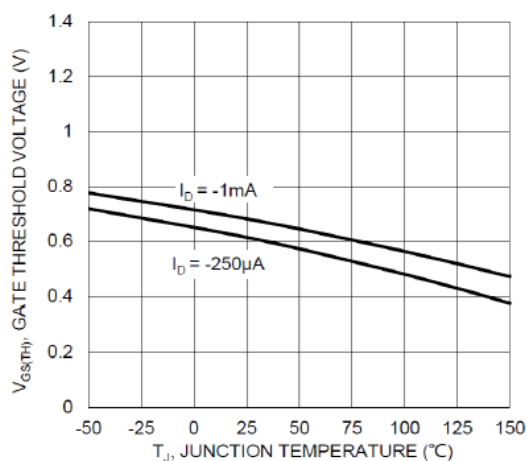
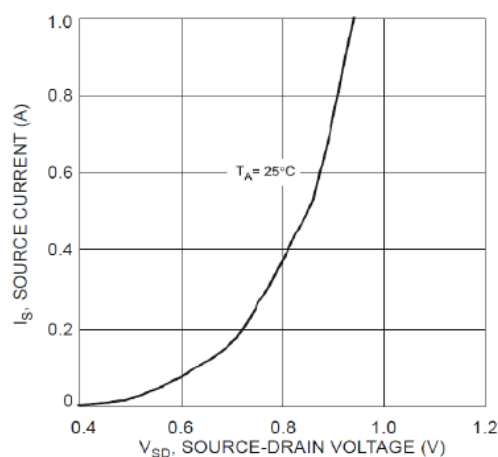
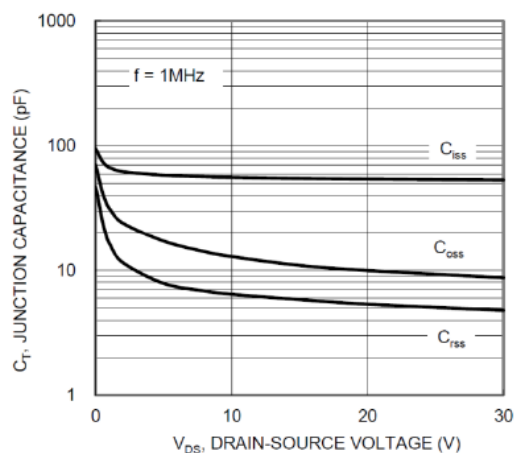
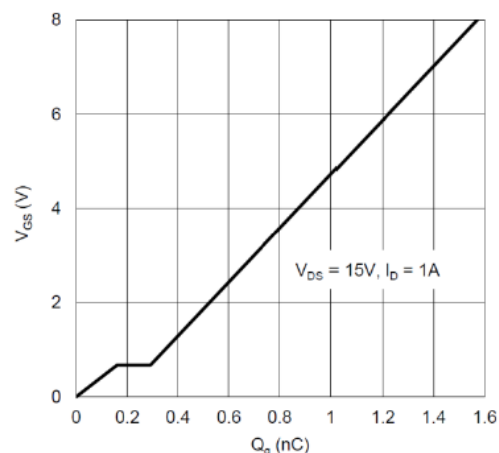
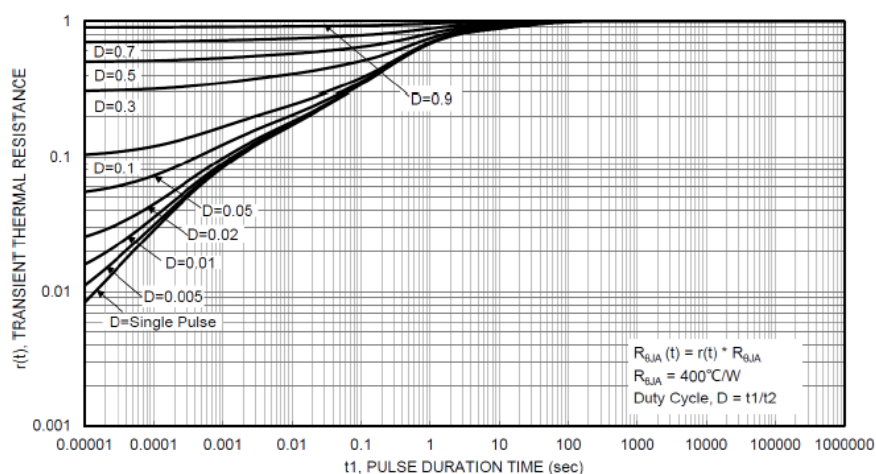
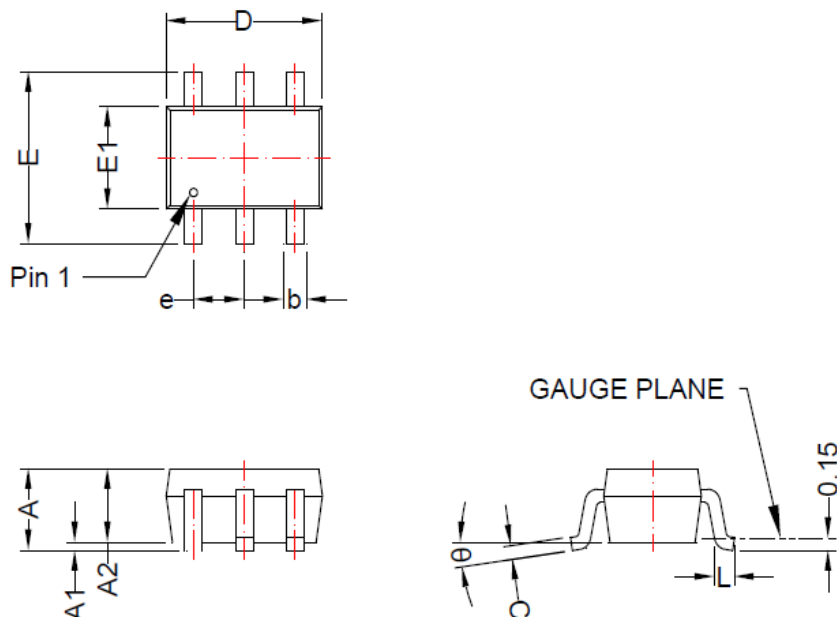


Fig. 6 On-Resistance Variation with  $T_J$

**Typical Performance Characteristics(continue)**

**Fig. 7 Gate Threshold Variation vs.  $T_A$** 

**Fig. 8 Diode Forward Voltage vs. Current**

**Fig. 9 Typical Capacitance**

**Fig. 10 Gate Charge**

**Fig. 11 Transient Thermal Response**

**Package Dimension:**

# **SOT-363**



THE D DIMENSION DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS, MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.2mm END. THE E1 DIMENSION DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION, INTERLEAD FLASH OR PROTRUSION SHALL NOT 0.20mm PER SIDE.

Dimensions				
Symbol	Millimeters		Inches	
	Min	Max	Min	Max
<b>A</b>	0.80	1.10	0.031	0.043
<b>A1</b>	0.00	0.10	0.000	0.004
<b>A2</b>	0.70	1.00	0.028	0.039
<b>b</b>	0.15	0.30	0.006	0.012
<b>c</b>	0.08	0.25	0.003	0.010
<b>D</b>	1.80	2.20	0.071	0.087
<b>E</b>	1.80	2.40	0.071	0.094
<b>E1</b>	1.15	1.35	0.045	0.053
<b>e</b>	0.65 BSC		0.026 BSC	
<b>L</b>	0.26	0.45	0.010	0.018
<b>θ</b>	0°	8°	0°	8°

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